Systems with Recognition and Learning Capability Based on Associative Memory

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1. Introduction

The effective implementation of pattern recognition and learning, which are basic functions for building artificial systems with capabilities similar to the human brain [1], is of great technical and practical importance. For this purpose our research group is developing a flexible architecture, which is based on the minimum-distance-search associative memory as a core element. A major first task is to efficiently implement the additional capabilities of recognition, learning and also judgement into the associative memory. Furthermore, a sufficient variety of distance measures for the basic pattern-matching proces has to be realized. In the COE program, we are mainly investigating such an associative memory-based systems, as schematically depicted in Fig. 1, to enable intelligent data processing similar to the human brain such as object-feature extraction, object recognition and learning or even judgement.

2. Distance Measure of an Associative Memory for **Efficient Pattern Recognition**

An associative memory has the capability of determining the nearest match between input-data words and a stored basis of reference-data words according to a distance measure. Especially for real-time recognition it will be necessary to implement fast matching up to large absolute minimum distances. In this project, we have developed a fullyparallel, combined digital/analog realization of the associative memory's search function, which allows short nearestmatch times with the Hamming as well as Manhattan distance measures (Fig. 2) [3, 4]. The chosen associativememory approach has in particular a high probability of being superior to the neural network approach, because there is no restriction on the type of the stored patterns and integration in conventional CMOS-technology is easy.

We have tested our architecture with chip designs in 0.6um (Hamming) [3] and in 0.35um (Manhattan) [9] CMOS technologies. A performance up to the equivalent of a 32bit computer with 150GOPS/mm² at low power dissipation of a few mW per mm² could be achieved. We have also proposed and verified a bank-type associative memory verified with test chips in 0.35um CMOS technology [2]. This bank-type architecture extends the possibility of fully-parallel nearest-match search to an in principle infinite space of reference patterns.

Recently, we have extended our associative-memory architecture to the realization of the Euclidean distance, which gives the correct distance between 2 points in vector space. Key points in our solution (Fig. 3) are the application of an analog squarer for each vector component and the avoidance of the square-root calculation, which has no influence on the winner determination.

3. Learning and Optimization of Reference-Patterns

A system concept with realizes high-speed pattern matching and automatic pattern learning has been developed on the basis of an associative memory with short-term and long-term storage regions (Fig. 4) [8]. The applied learning algorithm (Fig. 5) uses a 4-step process for each learning cycle: (1) Nearest-match determination (winner) in the associative memory for an input pattern. (2) Decision whether the input pattern is known by the system on the basis of the winner distance. (3) Increasing memorization strength (rank in the

storage space) of the winner if the input pattern is known. (4) Learning of the input pattern with a specific rank in the shortterm memory and forgetting the reference pattern with the lowest rank in the short-term memory if the input pattern is not known (Fig. 4). Furthermore, an optimization architecture for the learned reference patterns is developed [10].

A CMOS test chip, which implements a fully-parallel associative memory with 64 patterns, the pattern-learning algorithm and the pattern-optimization algorithm has been designed and fabricated (Fig. 6) and is now under measurement.

4. Cell-Network Based Real-time Image Segmentation

Image segmentation is the extraction process of all objects from natural input images and is the necessary first step of object-oriented image processing such as object recognition or object tracking. In this project, we have proposed a cellnetwork-based digital image segmentation algorithm/architecture with pixel parallel processing for gray-scale/color images in real-time applications (Fig. 7) [5, 6]. A CMOS test-chip for the cell-network, which is the main functional stage, has been fabricated, in a 0.35um CMOS technology and verifies the effectiveness of our proposal. In the performance verification of the test-chip, high speed segmentation in <9.5usec and low power dissipation of <36.4mW@10MHz are measured. The extrapolation results to larger image sizes suggest, that QVGA-size image segmentation will be possible within 300usec @10MHz at the 90nm CMOS technology node. Furthermore, we have proposed a low-power and hardware-efficient pipelined segmentation architecture for VGA-size motion pictures, which applies a subdivided-image approach (SIA) for compact implementation and a boundary-active-only (BAO) scheme for lowpower dissipation [7]. We have verified the effectiveness of the proposed architecture with a 51mm² test-circuit in 0.35um CMOS technology for the segmentation-network core consisting of 41x33 cells (Fig. 8). The segmentation performance for a VGA-size input image is 21.8mW power dissipation and 7.49msec segmentation time at 10MHz clock frequency.

5. Conclusion

An overview over our reseach work on an associative memory-based system with recognition and learning capability has been given. The next steps towards the complete system include architecture/circuit development for the adaptive pattern learning unit and the feature-extraction unit. This requires also the selection of concrete application examples and the development of a prototype system with recognition and learning capability.

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Figure 1: Structure of envisaged associative memory-based systems for the case of a visual input and illustrated with the example of recognizing and learning different types of cars.



Figure 3: Architecture concept for an associative memory with fully-parallel minimum Euclidean-distance search.



Figure 5: Flow chart of proposed associativememory-based pattern-learning algorithm.



Figure 7: Block diagram of the cell-network-based image segmentation architecture with subdivided-image approach (SIA).



Figure 2: Block diagram of the compact-associative-memory architecture with fast fully-parallel match capability according to the Hamming/Manhattan distance.



Figure 4: Learning concept based on a short/long term memory.



Figure 6: Associative-memory-based automatic pattern learning chip with 64 patterns. Long/short-term-memory size as well as the recognition threshold in the algorithm can be set externally.



Figure 8: Die photo of the cell-network with BAO including 41x33 cells designed in a 0.35um 3-metal CMOS technology. The layout of cell and connection-weight-register blocks is magnified on the right side.



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